



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts,Customers Priority,Honest Operation,and Considerate Service",our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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High Voltage IGBT with Diode

(Electrically Isolated Back Surface)

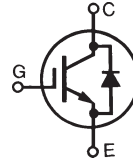
IXGR 35N120BD1

$$V_{CES} = 1200 \text{ V}$$

$$I_{C25} = 54 \text{ A}$$

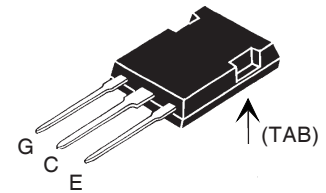
$$V_{CE(sat)} = 3.5 \text{ V}$$

$$t_{fi(typ)} = 160 \text{ ns}$$



Symbol	Test Conditions	Maximum Ratings	
V_{CES}	$T_J = 25^\circ\text{C}$ to 150°C	1200	V
V_{CGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GE} = 1 \text{ M}\Omega$	1200	V
V_{GES}	Continuous	± 20	V
V_{GEM}	Transient	± 30	V
I_{C25}	$T_C = 25^\circ\text{C}$	54	A
I_{C110}	$T_C = 110^\circ\text{C}$	28	A
I_{F110}	$T_C = 110^\circ\text{C}$	8	A
I_{CM}	$T_C = 25^\circ\text{C}$, 1 ms	200	A
SSOA (RBSOA)	$V_{GE} = 15 \text{ V}$, $T_J = 125^\circ\text{C}$, $R_G = 10 \Omega$ Clamped inductive load	$I_{CM} = 120$ @ $0.8 V_{CES}$	A
P_C	$T_C = 25^\circ\text{C}$	250	W
T_J		-55 ... +150	$^\circ\text{C}$
T_{JM}		150	$^\circ\text{C}$
T_{stg}		-55 ... +150	$^\circ\text{C}$
V_{ISOL}	50/60 Hz, RMS, $t = 1 \text{ min}$ $I_{SOL} = 1 \text{ mA}$, $t = 1 \text{ s}$	2500	V~
		3000	V~
F_C	Mounting force	22...130/5...29	N/lb
	Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s	300	$^\circ\text{C}$
Weight		6	g

ISOPLUS247 (IXGR)



G = Gate
E = Emitter
C = Collector
TAB = Electrically Isolated

Features

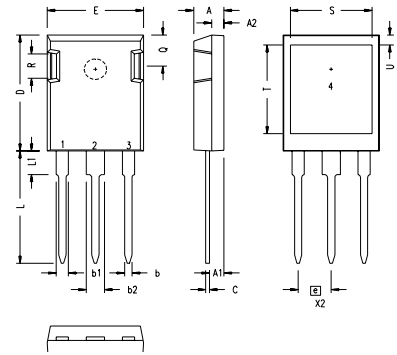
- Silicon chip on DCB substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- IGBT and anti-parallel FRED for resonant power supplies
 - Induction heating
 - Rice cookers
- MOS Gate turn-on
 - drive simplicity
- Fast Recovery Expitaxial Diode (FRED)
 - soft recovery with low I_{RM}

Advantages

- Saves space (two devices in one package)
- Easy to mount
- Reduces assembly time and cost

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
$(T_J = 25^\circ\text{C}$, unless otherwise specified)				
$V_{GE(th)}$	$I_C = 250 \mu\text{A}$, $V_{CE} = V_{GE}$	2.5		5.0 V
I_{CES}	$V_{CE} = V_{CES}$ $V_{GE} = 0 \text{ V}$	$T = 25^\circ\text{C}$		50 μA
		$T = 125^\circ\text{C}$		250 μA
I_{GES}	$V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$			$\pm 100 \text{ nA}$
$V_{CE(sat)}$	$I_C = 35 \text{ A}$, $V_{GE} = 15 \text{ V}$ Note 2		2.8	3.5 V

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
g_{fs}	$I_C = 35\text{A}; V_{CE} = 10\text{V}$, Note 2.	28	38	S
C_{ies}			2300	pF
C_{oes}	$V_{CE} = 25\text{V}, V_{GE} = 0\text{V}, f = 1\text{MHz}$		190	pF
C_{res}			80	pF
Q_g			140	nC
Q_{ge}	$I_C = 40\text{A}, V_{GE} = 15\text{V}, V_{CE} = 0.5 V_{CES}$		20	nC
Q_{gc}			50	nC
$t_{d(on)}$	Inductive load, $T_J = 25^\circ\text{C}$		40	ns
t_{ri}	$I_C = 35\text{A}; V_{GE} = 15\text{V}$		50	ns
E_{on}	$V_{CE} = 0.8 V_{CES}; R_G = R_{off} = 3\ \Omega$		0.9	mJ
$t_{d(off)}$	Note 1.		270	500 ns
t_{fi}			160	300 ns
E_{off}			3.8	7.0 mJ
$t_{d(on)}$	Inductive load, $T_J = 125^\circ\text{C}$		45	ns
t_{ri}	$I_C = 35\text{A}; V_{GE} = 15\text{V}$		60	ns
E_{on}	$V_{CE} = 0.8 V_{CES}; R_G = R_{off} = 3\ \Omega$		1.9	mJ
$t_{d(off)}$	Note 1		380	ns
t_{fi}			400	ns
E_{off}			8.0	mJ
R_{thJC}				0.5 K/W
R_{thCK}			0.25	K/W

ISOPLUS247 Outline


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

- 1 - GATE
- 2 - DRAIN (COLLECTOR)
- 3 - SOURCE (EMITTER)
- 4 - NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
V_F	$I_F = 10\text{A}, V_{GE} = 0\text{V}$ $I_F = 10\text{A}, V_{GE} = 0\text{V}, T_J = 125^\circ\text{C}$			3.3 V 2.2 V
I_{RM}	$I_F = 10\text{A}; -di_F/dt = 100\text{A}/\mu\text{s}, V_R = 100\text{V}$		4.0	A
t_{rr}	$V_{GE} = 0\text{V}; T_J = 125^\circ\text{C}$		190	ns
t_{rr}	$I_F = 1\text{A}; -di_F/dt = 100\text{A}/\mu\text{s}; V_R = 30\text{V}, V_{GE} = 0\text{V}$		40	ns
R_{thJC}				2.5 K/W

- Notes:
- Switching times may increase for $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$, higher T_J or increased R_G .
 - Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$.

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:	4,835,592	4,931,844	5,049,961	5,237,481	6,162,665	6,404,065B1	6,683,344	6,727,585
	4,850,072	5,017,508	5,063,307	5,381,025	6,259,123B1	6,534,343	6,710,405B2	
	4,881,106	5,034,796	5,187,117	5,486,715	6,306,728 B1	6,583,505	6,710,463	